January 2001

FDC6312P Dual P-Channel 1.8V PowerTrench[®] Specified MOSFET

General Description

SEMICONDUCTOR IM

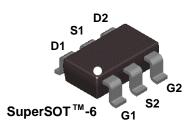
These P-Channel 1.8V specified MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain low gate charge for superior switching performance.

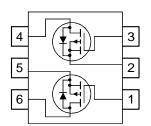
Applications

- Power management
- Load switch

Features

- -2.3 A, -20 V. $R_{DS(ON)} = 115 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 155 \text{ m}\Omega @ V_{GS} = -2.5 \text{ V}$ $R_{DS(ON)} = 225 \text{ m}\Omega @ V_{GS} = -1.8 \text{ V}$
- + High performance trench technology for extremely low $R_{_{\mbox{DS}(\mbox{ON})}}$
- SuperSOTTM-6 package: small footprint (72% smaller than standard SO-8); low profile (1mm thick)





Absolute Maximum Ratings T_{A=25°C} unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±8	V
ID	Drain Current – Continuous	(Note 1a)	-2.3	A
	- Pulsed		-7	
P _D	Power Dissipation for Single Operation	(Note 1a)	0.96	W
		(Note 1b)	0.9	
		(Note 1c)	0.7	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	130	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

Package Marking and Ordering Information

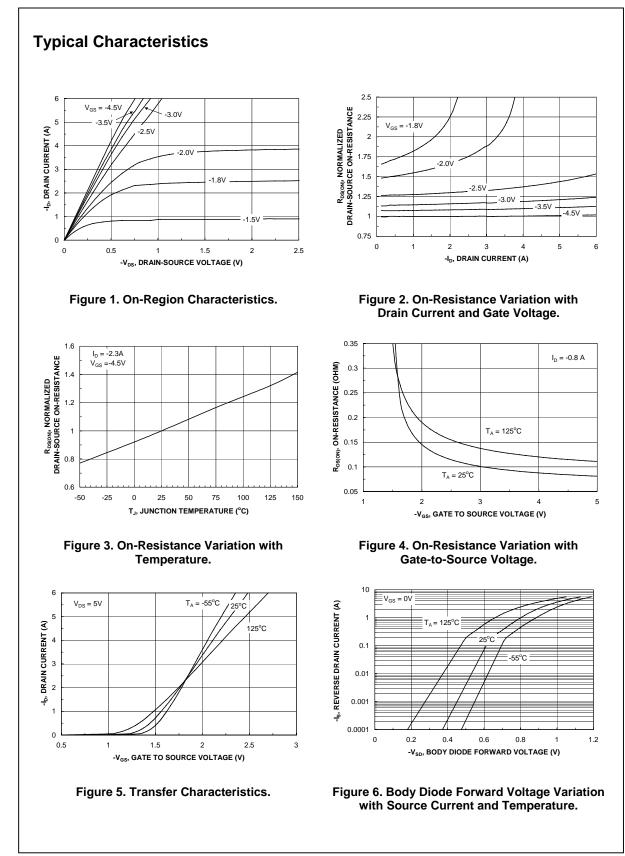
 Device Marking	Device	Reel Size	Tape width	Quantity	
.312	FDC6312P	13"	12mm	3000 units	

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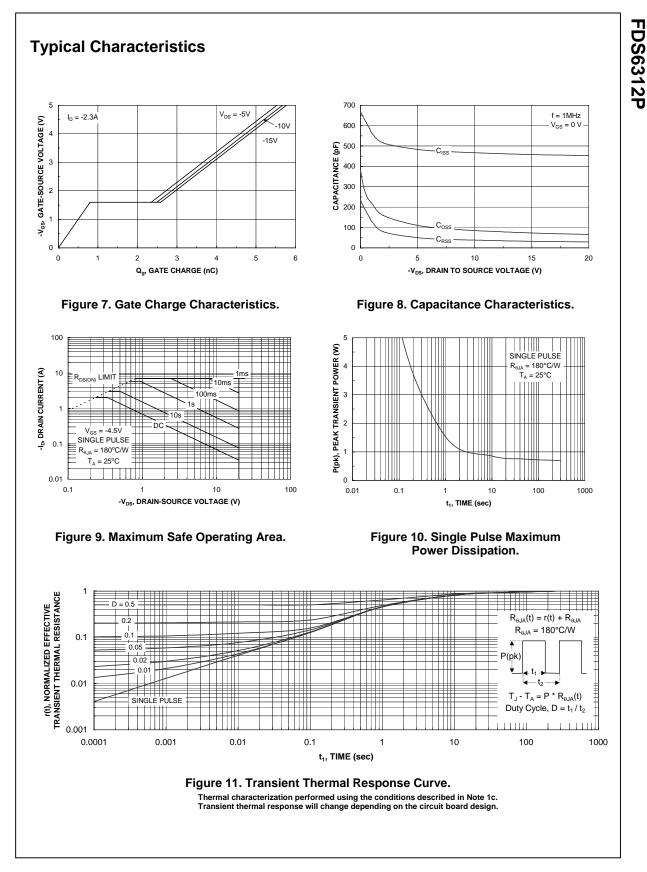
FDC6312P

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_{D} = -250 \mu A$	-20			V
$\Delta BV_{DSS} \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		-11		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 V$, $V_{GS} = 0 V$			-1	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 8 V$, $V_{DS} = 0 V$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -8 V$, $V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-0.4	-0.9	-1.5	V
$\Delta V_{GS(th)}$ ΔT_{J}	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		2		mV/°C
R _{DS(on)}	Static Drain–Source	$V_{GS} = -4.5 \text{ V}, \qquad I_D = -2.3 \text{ A}$		92	115	mΩ
	On-Resistance	$V_{GS} = -2.5 \text{ V}, I_D = -1.9 \text{ A}$		116	155	
		$V_{GS} = -1.8 \text{ V}, I_D = -1.6 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A}, T_J = 125^{\circ}\text{C}$		166 112	225 150	
1	On–State Drain Current	$V_{GS} = -4.5 \text{ V}, $	-7	112	150	A
I _{D(on)} g _{FS}	Forward Transconductance	$V_{\rm GS} = -4.3 \text{ V}, V_{\rm DS} = -3 \text{ V}$ $V_{\rm DS} = -5 \text{ V}, I_{\rm D} = -3.5 \text{ A}$	_/	5.3		S
•		$v_{\rm DS} = 0.0$ Å		0.0		0
	c Characteristics			407		
Ciss	Input Capacitance	$V_{DS} = -10 V$, $V_{GS} = 0 V$,		467		pF
Coss	Output Capacitance	f = 1.0 MHz		85 38		pF
C _{rss}	Reverse Transfer Capacitance			30		pF
	g Characteristics (Note 2)			r —	1	1
t _{d(on)}	Turn–On Delay Time	$V_{DD} = -10 V$, $I_D = -1 A$,		8	16	ns
tr	Turn–On Rise Time	$V_{GS} = -4.5 \text{ V}, \qquad R_{GEN} = 6 \ \Omega$		13	23	ns
t _{d(off)}	Turn–Off Delay Time			18	32	ns
t _f	Turn–Off Fall Time			8	16	ns
Qg	Total Gate Charge	$V_{DS} = -10 \text{ V}, \qquad I_D = -2.3 \text{ A}, \\ V_{GS} = -4.5 \text{ V}$		4.4	7	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -4.5 V$		1.0		nC
Q_{gd}	Gate-Drain Charge			0.8		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Source	e Diode Forward Current			-0.8	A
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_{S} = -0.8 A$ (Note 2)		-0.7	-1.2	V
the drain pins.	n of the junction-to-case and case-to-ambient then R_{eJC} is guaranteed by design while R_{eCA} is detern a) 130 °C/W when mounted on a 0.125 in ² pad of 2 oz. copper.		ଚ	as the solde 180°/W wi minimum j	nen mounte	
cale 1 : 1 on let	ter size paper					

FDC6312P Rev C (W)



FDS6312P



FDC6312P Rev C (W)

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